



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Transcat – Palm Beach Gardens

10415 Riverside Drive, Suite 107
Palm Beach Gardens, FL 33410

Fulfills the requirements of

ISO/IEC 17025:2017

and national standards

**ANSI/NCSL Z540-1-1994 (R2002) AND
ANSI/NCSL Z540.3-2006 (R2013)**

In the field of

CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

A handwritten signature in black ink, appearing to be 'J. Stine', is positioned above a horizontal line.

Jason Stine, Vice President

Expiry Date: 07 September 2027
Certificate Number: AC-2489.25



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

AND

ANSI/NCSL Z540-1-1994 (R2002)

ANSI/NCSL Z540.3-2006 (R2013)

Transcat – Palm Beach Gardens

10415 Riverside Drive, Suite 107

Palm Beach Gardens, FL 33410

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CALIBRATION

ISO/IEC 17025 Accreditation Granted: **02 September 2025**

Certificate Number: **AC-2489.25** Certificate Expiry Date: **07 September 2027**

Acoustics and Vibration

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Sound Measuring Equipment	125 Hz to 2 kHz	0.45 dB	Comparison to GenRad 1986 Sound Level Calibrator
	(74 to 104) dB	0.33 dB	
	114 dB	0.72 dB	
	4 kHz	0.6 dB	
	(74 to 104) dB		
	114 dB		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Measure ¹	(0.2 to 20) μ A	0.2 % of reading + 2.5 nA	Comparison to Fluke 8588A 8.5 Digit Multimeter
	1 Hz to 2 kHz	0.2 % of reading + 2.5 nA	
	(2 to 10) kHz	0.2 % of reading + 2.5 nA	
	(10 to 30) kHz	0.2 % of reading + 2.5 nA	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Measure ¹	(20 to 200) μ A		Comparison to Fluke 8588A 8.5 Digit Multimeter
	1 Hz to 2 kHz	0.28 mA/A + 5 nA	
	(2 to 10) kHz	0.53 mA/A + 5 nA	
	(10 to 30) kHz	0.74 mA/A + 5 nA	
	(30 to 100) kHz	4.1 mA/A + 10 nA	
	(0.2 to 2) mA		
	1 Hz to 2 kHz	0.28 mA/A + 50 nA	
	(2 to 10) kHz	0.53 mA/A + 50 nA	
	(10 to 30) kHz	0.74 mA/A + 50 nA	
	(30 to 100) kHz	4.1 mA/A + 0.1 μ A	
	(2 to 20) mA		
	1 Hz to 2 kHz	0.28 mA/A + 0.5 μ A	
	(2 to 10) kHz	0.53 mA/A + 0.5 μ A	
	(10 to 30) kHz	0.74 mA/A + 0.5 μ A	
	(30 to 100) kHz	4.1 mA/A + 1 μ A	
	(20 to 200) mA		
1 Hz to 2 kHz		0.28 mA/A + 5 μ A	
(2 to 10) kHz		0.52 mA/A + 5 μ A	
(10 to 30) kHz		0.74 mA/A + 5 μ A	
(0.2 to 2) A			
1 Hz to 2 kHz		0.3 mA/A + 0.1 mA	
(2 to 10) kHz		0.56 mA/A + 0.1 mA	
(10 to 30) kHz		0.8 mA/A + 0.1 mA	
(2 to 20) A			
10 Hz to 2 kHz		0.84 mA/A + 0.5 mA	
(2 to 10) kHz		0.86 mA/A + 0.5 mA	
(20 to 30) A			
10 Hz to 2 kHz		0.84 mA/A + 12 mA	
(2 to 10) kHz		1.2 mA/A + 12 mA	
(10 to 100) A			Comparison to Ohms Labs CS-100 Precision Shunt, Fluke 8588A 8.5 Digit Multimeter
(50 to 60) Hz		0.23 mA/A + 5 mA	
400 Hz		1.1 mA/A + 5 mA	
1 kHz		2 mA/A + 5 mA	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source ¹	Up to 220 μ A (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz 220 μ A to 2.2 mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (2.2 to 22) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (22 to 220) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz 220 mA to 2.2 A 20 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz 2.2 A to 11 A 20 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.025 % of reading + 16 nA 0.016 % of reading + 10 nA 0.011 % of reading + 8 nA 0.028 % of reading + 12 nA 0.11 % of reading + 65 nA 0.025 % of reading + 40 nA 0.016 % of reading + 35 nA 0.011 % of reading + 35 nA 0.02 % of reading + 0.11 μ A 0.11 % of reading + 0.65 μ A 0.025 % of reading + 0.4 μ A 0.016 % of reading + 0.35 μ A 0.011 % of reading + 0.35 μ A 0.02 % of reading + 0.55 μ A 0.11% of reading + 5 μ A 0.025 % of reading + 4 μ A 0.016 % of reading + 3.5 μ A 0.011 % of reading + 2.5 μ A 0.02 % of reading + 3.5 μ A 0.11 % of reading + 10 μ A 0.025 % of reading + 35 μ A 0.045 % of reading + 80 μ A 0.7 % of reading + 0.16 mA 0.046 % of reading + 0.17 μ A 0.095 % of reading + 0.38 μ A 0.36 % of reading + 0.75 μ A	Comparison to Fluke 5730A Multiproduct Calibrator, Fluke 5725A Amplifier
AC Current – Source ¹	Up to 2 A (10 to 850) Hz (0.85 to 6) kHz (6 to 10) kHz 2 A to 20 A (10 to 850) Hz (0.85 to 6) kHz (6 to 10) kHz	0.009 % of reading + 40 μ A 0.04 % of reading + 80 μ A 1.6 % of reading + 62 mA 0.009 % of reading + 0.4 mA 0.04 % of reading + 0.8 mA 2.3 % of reading + 94 mA	Comparison to Fluke 5730A Multiproduct Calibrator, Fluke 52120A Current Amplifier



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source ¹	20 A to 120 A (10 to 850) Hz (0.85 to 6) kHz (6 to 10) kHz	0.009 % of reading + 2.4 mA 0.04 % of reading + 4.8 mA 3.1 % of reading + 0.7 A	Comparison to Fluke 5730A Multiproduct Calibrator, Fluke 52120A Current Amplifier
AC Clamp-on Ammeter ¹ (Toroidal Type) Transformer Type Sensor	(20 to 150) A (45 to 65) Hz (65 to 440) Hz (150 to 1 000) A (45 to 65) Hz (65 to 440) Hz	0.3 % of reading + 26 mA 0.83 % of reading + 47 mA 0.35 % of reading + 0.12 A 1.1 % of reading + 0.22 A	Comparison to Fluke 5520A Multiproduct Calibrator, Fluke 5500A/COIL 50-turn Coil
AC Clamp-on Ammeter ¹ (Non-Toroidal Type) Hall Effect Sensor	(20 to 150) A (45 to 65) Hz (65 to 440) Hz (150 to 1 000) A (45 to 65) Hz (65 to 440) Hz	0.57 % of reading + 0.25 A 1 % of reading + 0.25 A 0.6 % of reading + 0.9 A 1.3 % of reading + 0.92 A	Comparison to Fluke 5520A Multiproduct Calibrator, Fluke 5500A/COIL 50-turn Coil
AC Clamp-on Ammeter ¹ (Non-Toroidal Type) Hall Effect Sensor	(1 to 6) kA (10 to 300) Hz (1 to 2) kA (300 to 440) Hz (2 to 6) kA (300 to 440) Hz	0.62 % of reading 0.8 % of reading 0.66 % of reading	Comparison to Fluke 5520A Multiproduct Calibrator, Fluke 52120A Transconductance Amplifier, 6 kA Coil
AC Voltage – Measure ¹	(0.1 to 10) mV 1 Hz to 2 kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz	0.029 % of reading + 1.1 μV 0.037 % of reading + 1.1 μV 0.038 % of reading + 1.1 μV 0.3 % of reading + 0.78 μV 1 % of reading + 3.9 μV 2 % of reading + 3.9 μV	Comparison to Fluke 8588A 8.5 Digit Multimeter

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	(10 to 100) mV		Comparison to Fluke 8588A 8.5 Digit Multimeter
	1 Hz to 2 kHz	0.008 9 % of reading + 0.5 μV	
	(2 to 10) kHz	0.013 % of reading + 0.5 μV	
	(10 to 30) kHz	0.023 % of reading + 1 μV	
	(30 to 100) kHz	0.053 % of reading + 5 μV	
	(100 to 300) kHz	0.21 % of reading + 31 μV	
	300 kHz to 1 MHz	1 % of reading + 0.1 mV	
	(1 to 2) MHz	1.5 % of reading + 0.5 mV	
	(2 to 4) MHz	4.1 % of reading + 1 mV	
	(4 to 8) MHz	8.4 % of reading + 1 mV	
	(8 to 10) MHz	16 % of reading + 1 mV	
	(0.1 to 1) V		
	1 Hz to 2 kHz	0.007 7% of reading + 5 μV	
	(2 to 10) kHz	0.012 % of reading + 5 μV	
	(10 to 30) kHz	0.023 % of reading + 10 μV	
	(30 to 100) kHz	0.053 % of reading + 50 μV	
	(100 to 300) kHz	0.21 % of reading + 0.31 mV	
	300 kHz to 1 MHz	1 % of reading + 1 mV	
	(1 to 2) MHz	1.5 % of reading + 5 mV	
	(2 to 4) MHz	4 % of reading + 10 mV	
	(4 to 8) MHz	8.2 % of reading + 10 mV	
	(8 to 10) MHz	15 % of reading + 10 mV	
	(1 to 10) V		
	1 Hz to 2 kHz	0.007 6 % of reading + 50 μV	
	(2 to 10) kHz	0.012 % of reading + 50 μV	
	(10 to 30) kHz	0.023 % of reading + 0.1 mV	
	(30 to 100) kHz	0.053 % of reading + 0.5 mV	
	(100 to 300) kHz	0.21 % of reading + 3.1 mV	
	300 kHz to 1 MHz	1 % of reading + 10 mV	
	(1 to 2) MHz	1.5 % of reading + 50 mV	
(2 to 4) MHz	4 % of reading + 0.1 V		
(4 to 8) MHz	8.2 % of reading + 0.1 V		
(8 to 10) MHz	15 % of reading + 0.1 V		
(10 to 100) V			
1 Hz to 2 kHz	0.009 % of reading + 0.5 mV		
(2 to 10) kHz	0.011 % of reading + 0.5 mV		
(10 to 30) kHz	0.023 % of reading + 1 mV		
(30 to 100) kHz	0.059 % of reading + 5 mV		
(100 to 300) kHz	0.37 % of reading + 47 mV		
300 kHz to 1 MHz	1 % of reading + 0.5 V		



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	(100 to 1 050) V 1 Hz to 2 kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz	0.011 % of reading + 25 mV 0.011 % of reading + 25 mV 0.023 % of reading + 25 mV 0.059 % of reading + 0.1 V	Comparison to Fluke 8588A 8.5 Digit Multimeter
AC Voltage – Measure	Up to 40 mVp-p DC to 100 MHz (40 to 400) mVp-p DC to 100 MHz (400 to 500) mVp-p DC to 100 MHz	1.6 % of reading + 0.15 mV 1.6 % of reading + 1.5 mV 1.6 % of reading + 3 mV	Comparison to Differential Amplifier w/ Oscilloscope
AC High Voltage – Measure ¹	(0.7 to 5) kV 10 mHz to 10 Hz (10 to 30) Hz (30 to 50) Hz (50 to 70) Hz (70 to 100) Hz (100 to 200) Hz (200 to 450) Hz (450 to 600) Hz (5 to 30) kV 10 mHz to 10 Hz (10 to 30) Hz (30 to 50) Hz (50 to 70) Hz (70 to 100) Hz (100 to 200) Hz (200 to 450) Hz (450 to 600) Hz (30 to 50) kV 10 mHz to 10 Hz (10 to 30) Hz (30 to 50) Hz (50 to 70) Hz (70 to 100) Hz (100 to 200) Hz (200 to 450) Hz	0.14 % of reading + 0.17 V 0.12 % of reading + 0.29 V 0.099 % of reading + 0.37 V 0.068 % of reading + 0.37 V 0.099 % of reading + 0.37 V 0.099 % of reading + 0.37 V 0.48 % of reading + 0.17 V 0.47 % of reading + 0.17 V 0.19 % of reading + 2.4 V 0.13 % of reading + 2.4 V 0.11 % of reading + 2.4 V 0.077 % of reading + 2.4 V 0.11 % of reading + 2.4 V 0.11 % of reading + 2.4 V 0.7 % of reading + 2.4 V 1.4 % of reading + 2.4 V 0.24 % of reading + 2.5 V 0.18 % of reading + 2.5 V 0.13 % of reading + 2.5 V 0.10 % of reading + 2.5 V 0.13 % of reading + 2.5 V 0.69 % of reading + 2.5 V 2.9 % of reading + 2.5 V	Comparison to Vitretek 4700 High Voltage Meter and Associated High Voltage Probes



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC High Voltage – Measure ¹	(50 to 70) kV 10 mHz to 10 Hz (10 to 30) Hz (30 to 50) Hz (50 to 70) Hz (70 to 100) Hz (100 to 200) Hz (200 to 450) Hz	0.37 % of reading + 2.6 V 0.26 % of reading + 2.6 V 0.16 % of reading + 2.6 V 0.16 % of reading + 2.6 V 1.2 % of reading + 2.6 V 1.2 % of reading + 2.6 V 17 % of reading + 2.6 V	Comparison to Vitrek 4700 High Voltage Meter and Associated High Voltage Probes
AC Voltage – Source ¹	Up to 2.2 mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz (2.2 to 22) mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz (22 to 220) mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz	0.024 % of reading + 4 μV 0.009 % of reading + 4 μV 0.008 % of reading + 4 μV 0.02 % of reading + 4 μV 0.05 % of reading + 5 μV 0.11 % of reading + 10 μV 0.14 % of reading + 20 μV 0.27 % of reading + 20 μV 0.024 % of reading + 4 μV 0.009 % of reading + 4 μV 0.008 % of reading + 4 μV 0.02 % of reading + 4 μV 0.05 % of reading + 5 μV 0.11 % of reading + 10 μV 0.14 % of reading + 20 μV 0.27 % of reading + 20 μV 0.024 % of reading + 12 μV 0.009 % of reading + 7 μV 0.005 7 % of reading + 7 μV 0.012 % of reading + 7 μV 0.031 % of reading + 17 μV 0.066 % of reading + 20 μV 0.14 % of reading + 25 μV 0.27 % of reading + 45 μV	Comparison to Fluke 5730A Multiproduct Calibrator



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹	220 mV to 2.2 V		Comparison to Fluke 5730A Multiproduct Calibrator
	(10 to 20) Hz	0.024 % of reading + 40 μV	
	(20 to 40) Hz	0.009 % of reading + 15 μV	
	40 Hz to 20 kHz	0.004 2 % of reading + 8 μV	
	(20 to 50) kHz	0.006 7 % of reading + 10 μV	
	(50 to 100) kHz	0.008 5 % of reading + 30 μV	
	(100 to 300) kHz	0.034 % of reading + 80 μV	
	(300 to 500) kHz	0.1 % of reading + 0.2 mV	
	500 kHz to 1 MHz	0.17 % of reading + 0.3 mV	
	(2.2 to 22) V		
	(10 to 20) Hz	0.024 % of reading + 0.4 mV	
	(20 to 40) Hz	0.009 % of reading + 0.15 mV	
	40 Hz to 20 kHz	0.004 2 % of reading + 0.05 mV	
	(20 to 50) kHz	0.006 7 % of reading + 0.1 mV	
	(50 to 100) kHz	0.008 3 % of reading + 0.2 mV	
	(100 to 300) kHz	0.034 % of reading + 0.6 mV	
	(300 to 500) kHz	0.1 % of reading + 2 mV	
	500 kHz to 1 MHz	0.17 % of reading + 3.2 mV	
	(22 to 220) V		
	(10 to 20) Hz	0.024 % of reading + 4 mV	
(20 to 40) Hz	0.009 % of reading + 1.5 mV		
40 Hz to 20 kHz	0.005 2 % of reading + 0.6 mV		
(20 to 50) kHz	0.008 % of reading + 1 mV		
(50 to 100) kHz	0.015 % of reading + 2.5 mV		
(100 to 300) kHz	0.09 % of reading + 16 mV		
(300 to 500) kHz	0.44 % of reading + 40 mV		
500 kHz to 1 MHz	0.8 % of reading + 80 mV		
(220 to 250) V			
(15 to 50) Hz	0.03 % of reading + 16 mV		
(250 to 1 100) V			
50 Hz to 1 kHz	0.007 % of reading + 3.5 mV		
AC Voltage – Source ¹	(220 to 750) V		Comparison to Fluke 5730A Multiproduct Calibrator, Fluke 5725A Amplifier
	(30 to 50) kHz	0.06 % of reading + 11 mV	
	(50 to 100) kHz	0.06 % of reading + 11 mV	
	(220 to 1100) V		
	40 Hz to 1 kHz	0.009 % of reading + 4 mV	
	(1 to 20) kHz	0.017 % of reading + 6 mV	
(20 to 30) kHz	0.23 % of reading + 45 mV		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹ Wide-Band Voltage (50 Ω)	30 Hz to 500 kHz (0.33 to 1.1) mV (1.1 to 3.3) mV (3.3 to 11) mV (11 to 33) mV (33 to 110) mV (110 to 330) mV (0.33 to 1.1) V (1.1 to 3.5) V	0.62 % of reading + 0.78 μV 0.54 % of reading + 1.2 μV 0.54 % of reading + 3.1 μV 0.47 % of reading + 6.2 μV 0.47 % of reading + 16 μV 0.39 % of reading + 39 μV 0.39 % of reading + 0.16 mV 0.31 % of reading + 0.19 mV	Comparison to Fluke 5730A/05 Multiproduct Calibrator
AC Voltage – Source ¹ Wide-Band Flatness (50 Ω) 1 kHz Reference	(0.33 to 1.1) mV (10 to 30) Hz (30 to 119.99) Hz (120 to 1,199.9) kHz (1.2 to 11,999) kHz (12 to 119.99) kHz 120 kHz to 1,199.9 MHz (1.2 to 2) MHz (2 to 11.9) MHz (12 to 20) MHz (20 to 30) MHz (30 to 50) MHz (1.1 to 3.3) mV (10 to 30) Hz (30 to 119.99) Hz 120 Hz to 1,199.9 kHz (1.2 to 11,999) kHz (12 to 119.99) kHz 120 kHz to 1,199.9 MHz (1.2 to 2) MHz (2 to 11.9) MHz (12 to 20) MHz (20 to 30) MHz (30 to 50) MHz	0.23 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.16 % of reading + 1.2 μV 0.16 % of reading + 1.2 μV 0.31 % of reading + 1.2 μV 0.47 % of reading + 1.2 μV 1.2 % of reading + 5.8 μV 2.3 % of reading + 5.8 μV 0.23 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading + 1.2 μV 0.078 % of reading + 1.2 μV 0.23 % of reading + 1.2 μV 0.39 % of reading + 1.2 μV 1.2 % of reading + 1.2 μV 2.3 % of reading + 1.2 μV	Comparison to Fluke 5730A/05 Multiproduct Calibrator



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹ Wide-Band Flatness (50 Ω) 1 kHz Reference	(3.3 to 11) mV		Comparison to Fluke 5730A/05 Multiproduct Calibrator
	(10 to 30) Hz	0.23 % of reading	
	(30 to 119.99) Hz	0.078 % of reading	
	120 Hz to 1.199 9 kHz	0.078 % of reading	
	(1.2 to 11.999) kHz	0.078 % of reading	
	(12 to 119.99) kHz	0.078 % of reading	
	120 kHz to 1.199 9 MHz	0.078 % of reading + 1.2 μV	
	(1.2 to 2) MHz	0.078 % of reading + 1.2 μV	
	(2 to 11.9) MHz	0.16 % of reading + 1.2 μV	
	(12 to 20) MHz	0.31 % of reading + 1.2 μV	
	(20 to 30) MHz	0.78 % of reading + 1.2 μV	
	(30 to 50) MHz	1.6 % of reading + 1.2 μV	
	(11 to 33) mV		
	(10 to 30) Hz	0.23 % of reading	
	(30 to 119.99) Hz	0.078 % of reading	
	120 Hz to 1.199 9 kHz	0.078 % of reading	
	(1.2 to 11.999) kHz	0.078 % of reading	
	(12 to 119.99) kHz	0.078 % of reading	
	120 kHz to 1.199 9 MHz	0.078 % of reading + 1.2 μV	
	(11 to 16.5) mV		
	(1.2 to 2) MHz	0.16 % of reading + 1.2 μV	
	(2 to 11.9) MHz	0.23 % of reading + 1.2 μV	
	(12 to 20) MHz	0.39 % of reading + 1.2 μV	
	(20 to 30) MHz	0.85 % of reading + 1.2 μV	
	(30 to 50) MHz	1.6 % of reading + 1.2 μV	
	(16.5 to 33) mV		
	(1.2 to 2) MHz	0.078 % of reading + 1.2 μV	
	(2 to 11.9) MHz	0.16 % of reading + 1.2 μV	
(12 to 20) MHz	0.31 % of reading + 1.2 μV		
(20 to 30) MHz	0.78 % of reading + 1.2 μV		
(30 to 50) MHz	1.6 % of reading + 1.2 μV		
(33 to 110) mV			
(10 to 30) Hz	0.23 % of reading		
(30 to 119.99) Hz	0.078 % of reading		
120 Hz to 1.199 9 kHz	0.078 % of reading		
(1.2 to 11.999) kHz	0.078 % of reading		
(12 to 119.99) kHz	0.078 % of reading		
120 Hz to 1.199 9 MHz	0.078 % of reading + 1.2 μV		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹ Wide-Band Flatness (50 Ω) 1 kHz Reference	(33 to 55) mV		Comparison to Fluke 5730A/05 Multiproduct Calibrator
	(1.2 to 2) MHz	0.16 % of reading + 1.2 μV	
	(2 to 11.9) MHz	0.23 % of reading + 1.2 μV	
	(12 to 20) MHz	0.39 % of reading + 1.2 μV	
	(20 to 30) MHz	0.85 % of reading + 1.2 μV	
	(30 to 50) MHz	1.6 % of reading + 1.2 μV	
	(55 to 110) mV		
	(1.2 to 2) MHz	0.078 % of reading + 1.2 μV	
	(2 to 11.9) MHz	0.16 % of reading + 1.2 μV	
	(12 to 20) MHz	0.31 % of reading + 1.2 μV	
	(20 to 30) MHz	0.78 % of reading + 1.2 μV	
	(30 to 50) MHz	1.6 % of reading + 1.2 μV	
	(110 to 330) mV		
	(10 to 30) Hz	0.23 % of reading	
	(30 to 119.99) Hz	0.078 % of reading	
	120 Hz to 1.199 9 kHz	0.078 % of reading	
	(1.2 to 11.999) kHz	0.078 % of reading	
	(12 to 119.99) kHz	0.078 % of reading	
	120 Hz to 1.199 9 MHz	0.078 % of reading + 1.2 μV	
	(110 to 165) mV		
	(1.2 to 2) MHz	0.16 % of reading + 1.2 μV	
	(2 to 11.9) MHz	0.23 % of reading + 1.2 μV	
	(12 to 20) MHz	0.39 % of reading + 1.2 μV	
	(20 to 30) MHz	0.85 % of reading + 1.2 μV	
	(30 to 50) MHz	1.6 % of reading + 1.2 μV	
	(165 to 330) mV		
	(1.2 to 2) MHz	0.078 % of reading + 1.2 μV	
	(2 to 11.9) MHz	0.16 % of reading + 1.2 μV	
(12 to 20) MHz	0.31 % of reading + 1.2 μV		
(20 to 30) MHz	0.78 % of reading + 1.2 μV		
(30 to 50) MHz	1.6 % of reading + 1.2 μV		
(0.33 to 1.1) V			
(10 to 30) Hz	0.23 % of reading		
(30 to 119.99) Hz	0.078 % of reading		
120 Hz to 1.199 9 kHz	0.078 % of reading		
(1.2 to 11.999) kHz	0.078 % of reading		
(12 to 119.99) kHz	0.078 % of reading		
120 Hz to 1.199 9 MHz	0.078 % of reading + 1.2 μV		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
<p>AC Voltage – Source ¹ Wide-Band Flatness (50 Ω) 1 kHz Reference</p>	<p>(0.33 to 0.55) V (1.2 to 2) MHz (2 to 11.9) MHz (12 to 20) MHz (20 to 30) MHz (30 to 50) MHz (0.55 to 1.1) V (1.2 to 2) MHz (2 to 11.9) MHz (12 to 20) MHz (20 to 30) MHz (30 to 50) MHz (1.1 to 3.5) V (10 to 30) Hz (30 to 119.99) Hz 120 Hz to 1.199 9 kHz (1.2 to 11.999) kHz (12 to 119.99) kHz 120 Hz to 1.199 9 MHz (1.1 to 1.75) V (1.2 to 2) MHz (2 to 11.9) MHz (12 to 20) MHz (20 to 30) MHz (30 to 50) MHz (1.75 to 3.5) V (1.2 to 2) MHz (2 to 11.9) MHz (12 to 20) MHz (20 to 30) MHz (30 to 50) MHz</p>	<p>0.16 % of reading + 1.2 μV 0.23 % of reading + 1.2 μV 0.39 % of reading + 1.2 μV 0.85 % of reading + 1.2 μV 1.6 % of reading + 1.2 μV 0.078 % of reading + 1.2 μV 0.16 % of reading + 1.2 μV 0.31 % of reading + 1.2 μV 0.78 % of reading + 1.2 μV 1.6 % of reading + 1.2 μV 0.23 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading + 1.2 μV 0.16 % of reading + 1.2 μV 0.23 % of reading + 1.2 μV 0.39 % of reading + 1.2 μV 0.85 % of reading + 1.2 μV 1.6 % of reading + 1.2 μV 0.078 % of reading + 1.2 μV 0.16 % of reading + 1.2 μV 0.31 % of reading + 1.2 μV 0.78 % of reading + 1.2 μV 1.6 % of reading + 1.2 μV</p>	<p>Comparison to Fluke 5730A/05 Multiproduct Calibrator</p>
<p>DC Current – Measure ¹</p>	<p>(0 to 20) μA (20 to 200) μA (0.2 to 2) mA (2 to 20) mA (20 to 200) mA (0.2 to 2) A (2 to 20) A (20 to 30) A</p>	<p>29 μA/A + 0.4 nA 10 μA/A + 0.39 nA 9.9 μA/A + 3.9 nA 15 μA/A + 39 nA 58 μA/A + 1 μA 0.13 mA/A + 0.1 mA 0.23 mA/A + 0.4 mA 0.55 mA/A + 4.4 mA</p>	<p>Comparison to Fluke 8588A 8.5 Digit Multimeter</p>

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Current – Measure ¹	(10 to 100) A	0.15 mA/A + 3 mA	Comparison to Ohm Labs CS-100 Current Shunt, Fluke 8588A 8.5 Digit Multimeter
DC Current – Source ¹	Up to 220 μ A (0.22 to 2.2) mA (2.2 to 22) mA (22 to 220) mA 220 mA to 2.2 A	40 μ A/A + 6 nA 35 μ A/A + 7 nA 35 μ A/A + 40 nA 45 μ A/A + 0.7 μ A 80 μ A/A + 12 μ A	Comparison to Fluke 5730A Multiproduct Calibrator
DC Current – Source ¹	(2.2 to 11) A Up to 2 A (2 to 20) A	0.036 % of reading + 0.48 mA 0.012 % of reading + 0.16 mA 0.012 % of reading + 1.6 mA	Comparison to Fluke 5730A Multiproduct Calibrator, Fluke 5725A Amplifier
DC Current – Source ¹	(20 to 120) A	0.012 % of reading + 9.6 mA	Comparison to Fluke 5730A Multiproduct Calibrator, Fluke 52120A Current Amplifier
DC Clamp-on Ammeter ¹ (Non-Toroidal Type) Hall Effect Sensor	(20 to 150) A (150 to 1 000) A	0.5 % of reading + 0.14 A 0.52 % of reading + 0.5 A	Comparison to Fluke 5522A Multiproduct Calibrator, Fluke 5500A/COIL 50-turn Coil
DC Clamp-on Ammeter ¹ (Non-Toroidal Type) Hall Effect Sensor	(1 to 5) kA	0.58 % of reading	Comparison to Fluke 5522A Multiproduct Calibrator, Current Coils
DC Voltage – Measure ¹	(0 to 200) mV (0.2 to 2) V (2 to 20) V (20 to 200) V (200 to 1050) V	7.7 μ V/V + 0.2 μ V 2.9 μ V/V + 0.3 μ V 2.9 μ V/V + 0.47 μ V 4.3 μ V/V + 30 μ V 4.4 μ V/V + 0.5 mV	Comparison to Fluke 8588A 8.5 Digit Multimeter
DC Voltage – Source ¹	(0 to 220) mV 220 mV to 2.2 V (2.2 to 11) V (11 to 22) V (22 to 220) V 220 V to 1100 V	7.5 μ V/V + 0.4 μ V 5 μ V/V + 0.7 μ V 3.5 μ V/V + 2.5 μ V 3.5 μ V/V + 4 μ V 5 μ V/V + 40 μ V 6.5 μ V/V + 0.4 mV	Comparison to Fluke 5730A Multiproduct Calibrator



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC High Voltage – Measure ¹	(1 to 10) kV (10 to 20) kV (20 to 30) kV (30 to 40) kV (40 to 50) kV (50 to 60) kV (60 to 70) kV (70 to 80) kV (80 to 90) kV (90 to 100) kV	0.039 % of reading + 0.092 V 0.038 % of reading + 2.4 V 0.041 % of reading + 2.4 V 0.047 % of reading + 2.4 V 0.056 % of reading + 2.4 V 0.071 % of reading + 2.4 V 0.089 % of reading + 2.4 V 0.12 % of reading + 2.5 V 0.15 % of reading + 2.5 V 0.17 % of reading + 2.5 V	Comparison to Vitrek 4700 High Voltage Meter, Associated High Voltage Probes
Resistance – Measure ¹	(0 to 2) Ω (2 to 20) Ω (20 to 200) Ω (0.2 to 2) kΩ (2 to 20) kΩ (20 to 200) kΩ (0.2 to 2) MΩ (2 to 20) MΩ (20 to 200) MΩ (0.2 to 2) GΩ	16 μΩ/Ω + 4 μΩ 10 μΩ/Ω + 14 μΩ 9.2 μΩ/Ω + 47 μΩ 9.1 μΩ/Ω + 0.47 mΩ 9.2 μΩ/Ω + 4.7 mΩ 9.3 μΩ/Ω + 47 mΩ 11 μΩ/Ω + 1 Ω 19 μΩ/Ω + 0.1 kΩ 0.12 mΩ/Ω + 10 kΩ 0.13 % of reading + 1 MΩ	Comparison to Fluke 8588A 8.5 Digit Multimeter
Low Current Resistance – Measure ¹	Up to 2 Ω (2 to 20) Ω (20 to 200) Ω (0.2 to 2) kΩ (2 to 20) kΩ (20 to 200) kΩ (0.2 to 2) MΩ (2 to 20) MΩ (20 to 200) MΩ (0.2 to 2) GΩ	17 μΩ/Ω + 4 μΩ 10 μΩ/Ω + 14 μΩ 17 μΩ/Ω + 0.2 mΩ 18 μΩ/Ω + 2 mΩ 22 μΩ/Ω + 20 mΩ 22 μΩ/Ω + 62 mΩ 26 μΩ/Ω + 1 Ω 0.38 mΩ/Ω + 0.30 kΩ 0.13 % of reading + 10 kΩ 0.13 % of reading + 1.0 MΩ	Comparison to Fluke 8588A 8.5 Digit Multimeter
High Voltage Resistance – Measure ¹	(2 to 20) MΩ (20 to 200) MΩ (0.2 to 2) GΩ (2 to 20) GΩ	17 μΩ/Ω + 10 Ω 68 μΩ/Ω + 0.1 kΩ 0.23 mΩ/Ω + 0.1 MΩ 0.13 % of reading + 10 MΩ	Comparison to Fluke 8588A 8.5 Digit Multimeter



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Resistance – Source ¹ (Simulation)	(0 to 11) Ω	32 μΩ/Ω + 0.78 mΩ	Comparison to Fluke 5522A Multiproduct Calibrator
	(11 to 33) Ω	24 μΩ/Ω + 1.2 mΩ	
	(33 to 111) Ω	22 μΩ/Ω + 1.1 mΩ	
	(110 to 330) Ω	22 μΩ/Ω + 1.6 mΩ	
	330 Ω to 1.1 kΩ	22 μΩ/Ω + 1.6 mΩ	
	(1.1 to 3.3) kΩ	22 μΩ/Ω + 1.6 mΩ	
	(3.3 to 11) kΩ	22 μΩ/Ω + 1.6 mΩ	
	(11 to 33) kΩ	22 μΩ/Ω + 0.16 Ω	
	(33 to 110) kΩ	22 μΩ/Ω + 0.16 Ω	
	(110 to 330) kΩ	27 μΩ/Ω + 1.6 Ω	
	330 kΩ to 1.19 MΩ	26 μΩ/Ω + 1.6 Ω	
	(1.1 to 3.3) MΩ	66 μΩ/Ω + 23 Ω	
	(3.3 to 11) MΩ	100 μΩ/Ω + 39 Ω	
	(11 to 33) MΩ	190 μΩ/Ω + 1.9 kΩ	
(33 to 110) MΩ	410 μΩ/Ω + 2.3 kΩ		
(110 to 330) MΩ	0.23 % of reading + 78 kΩ		
330 MΩ to 1.1 GΩ	12 % of reading + 0.39 MΩ		
Resistance – Source ¹ (Fixed-point Simulation)	0 Ω	40 μΩ	Comparison to Fluke 5730A Multiproduct Calibrator
	1 Ω	95 μΩ/Ω	
	1.9 Ω	95 μΩ/Ω	
	10 Ω	23 μΩ/Ω	
	19 Ω	23 μΩ/Ω	
	100 Ω	10 μΩ/Ω	
	190 Ω	10 μΩ/Ω	
	1 kΩ	6.5 μΩ/Ω	
	1.9 kΩ	6.5 μΩ/Ω	
	10 kΩ	6.5 μΩ/Ω	
	19 kΩ	6.5 μΩ/Ω	
	100 kΩ	8.5 μΩ/Ω	
	190 kΩ	8.5 μΩ/Ω	
	1 MΩ	13 μΩ/Ω	
	1.9 MΩ	18 μΩ/Ω	
	10 MΩ	40 μΩ/Ω	
19 MΩ	47 μΩ/Ω		
100 MΩ	0.1 mΩ/Ω		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Resistance – Source ¹ (Fixed Artifacts)	1 mΩ 10 mΩ 100 mΩ 1 Ω 10 GΩ 100 GΩ	0.16 mΩ/Ω 0.13 mΩ/Ω 0.1 mΩ/Ω 43 μΩ/Ω 63 MΩ 1.3 GΩ	Comparison to Ohms Labs CS-100 Current Shunt; IET DCCS-0.01, IET DCCS-0.1, IET DCCS-1 Standard Resistors, Decade Resistance Standard
Resistance – Source ¹ (Variable Artifact)	(100 to 1 000) kΩ (1 to 10) MΩ (10 to 100) MΩ (100 to 1 000) MΩ (1 to 10) GΩ (10 to 100) GΩ (100 to 1 000) GΩ	0.037 % of reading 0.037 % of reading + 1.2 μΩ/Ω/V 0.12 % of reading + 1.2 μΩ/Ω/V 0.23 % of reading + 1.2 μΩ/Ω/V 0.59 % of reading + 1.2 μΩ/Ω/V 1.2 % of reading + 1.2 μΩ/Ω/V 1.2 % of reading + 1.2 μΩ/Ω/V	Comparison to IET HRRS-B-7-100k-10kV Decade Resistor
Capacitance – Measure ¹	Up to 2 nF (2 to 20) nF (20 to 200) nF (0.2 to 2) μF (2 to 20) μF (20 to 200) μF (0.2 to 2) mF (2 to 20) mF (20 to 200) mF	0.19 % of reading + 1 pF 0.081 % of reading + 2 pF 0.049 % of reading + 10 pF 0.041 % of reading + 0.1 nF 0.042 % of reading + 1 nF 0.061 % of reading + 10 nF 0.061 % of reading + 0.1 μF 0.071 % of reading + 1 μF 0.072 % of reading + 10 μF	Comparison to Fluke 8588A 8.5 Digit Multimeter
Capacitance – Source ¹ (Variable Artifact)	1 kHz (50 to 190) pF	0.6 % of reading + 5 pF	Comparison to Decade Capacitance Standard
Capacitance – Source ¹ (Simulation)	(220 to 400) pF 10 Hz to 10 kHz (0.4 to 1.1) nF 10 Hz to 10 kHz (1.1 to 3.3) nF 10 Hz to 3 kHz (3.3 to 11) nF 10 Hz to 3 kHz (11 to 33) nF 10 Hz to 1 kHz	0.4 % of reading + 7.8 pF 0.4 % of reading + 7.8 pF 0.4 % of reading + 7.8 pF 0.4 % of reading + 7.8 pF 0.21 % of reading + 7.8 pF 0.2 % of reading + 78 pF	Comparison to Fluke 5522A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment		
Capacitance – Source ¹ (Simulation)	(33 to 110) nF 10 Hz to 1 kHz	0.21 % of reading + 78 pF	Comparison to Fluke 5522A Multiproduct Calibrator		
	(110 to 330) nF 10 Hz to 1 kHz	0.2 % of reading + 0.23 nF			
	(0.33 to 1.1) μF (10 to 600) Hz	0.21 % of reading + 0.78 nF			
	(1.1 to 3.3) μF (10 to 300) Hz	0.21 % of reading + 2.3 nF			
	(3.3 to 11) μF (10 to 150) Hz	0.2 % of reading + 7.8 nF			
	(11 to 33) μF (10 to 120) Hz	0.32 % of reading + 23 nF			
	(33 to 110) μF (10 to 80) Hz	0.37 % of reading + 78 nF			
	(110 to 330) μF DC to 50 Hz	0.38 % of reading + 0.23 μF			
	(0.33 to 1.1) mF DC to 20 Hz	0.35 % of reading + 0.78 μF			
	(1.1 to 3.3) mF DC to 6 Hz	0.35 % of reading + 2.3 μF			
	(3.3 to 11) mF DC to 2 Hz	0.35 % of reading + 7.8 μF			
	(11 to 33) mF DC to 0.6 Hz	0.58 % of reading + 23 μF			
	(33 to 110) mF DC to 0.2 Hz	0.85 % of reading + 78 μF			
	Electrical Simulation of Thermocouple Indicating Devices – Source/Measure ¹	Type B			Comparison to Ectron 1140A Thermocouple Calibrator/Simulator
		(250 to 350) °C		1.2 °C	
(350 to 445) °C		0.9 °C			
(445 to 580) °C		0.71 °C			
(580 to 750) °C		0.55 °C			
(750 to 1 000) °C		0.45 °C			
(1 000 to 1 820) °C		0.35 °C			
Type C					
(0 to 250) °C		0.24 °C			
(250 to 1 000) °C		0.19 °C			
(1 000 to 1 500) °C		0.21 °C			
(1 500 to 1 800) °C		0.24 °C			
(1 800 to 2 000) °C		0.27 °C			
(2 000 to 2 250) °C	0.33 °C				
(2 250 to 2 315) °C	0.37 °C				

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicating Devices – Source/Measure ¹	Type E		Comparison to Ectron 1140A Thermocouple Calibrator/Simulator
	(-270 to -245) °C	1.6 °C	
	(-245 to -195) °C	0.24 °C	
	(-195 to -155) °C	0.12 °C	
	(-155 to -90) °C	0.095 °C	
	(-90 to 0) °C	0.08 °C	
	(0 to 15) °C	0.076 °C	
	(15 to 890) °C	0.064 °C	
	(890 to 1 000) °C	0.074 °C	
	Type J		
	(-210 to -180) °C	0.15 °C	
	(-180 to -120) °C	0.12 °C	
	(-120 to -50) °C	0.093 °C	
	(-50 to 990) °C	0.08 °C	
	(990 to 1 200) °C	0.094 °C	
	Type K		
	(-270 to -255) °C	2.5 °C	
	(-255 to -195) °C	0.85 °C	
	(-195 to -115) °C	0.16 °C	
	(-115 to -55) °C	0.12 °C	
	(-55 to 1 000) °C	0.087 °C	
	(1 000 to 1 372) °C	0.096 °C	
	Type N		
	(-270 to -260) °C	5.4 °C	
	(-260 to -200) °C	1.5 °C	
	(-200 to -140) °C	0.29 °C	
	(-140 to -70) °C	0.18 °C	
	(-70 to 25) °C	0.14 °C	
(25 to 160) °C	0.12 °C		
(160 to 1 300) °C	0.11 °C		
Type R			
(-50 to -30) °C	0.8 °C		
(-30 to 45) °C	0.69 °C		
(45 to 160) °C	0.49 °C		
(160 to 380) °C	0.35 °C		
(380 to 775) °C	0.3 °C		
(775 to 1 768) °C	0.26 °C		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicating Devices – Source/Measure ¹	Type S (-50 to -30) °C (-30 to 45) °C (45 to 105) °C (105 to 310) °C (310 to 615) °C (615 to 1 768) °C Type T (-270 to -255) °C (-255 to -240) °C (-240 to -210) °C (-210 to -150) °C (-180 to -40) °C (-40 to 100) °C (100 to 400) °C	0.76 °C 0.68 °C 0.49 °C 0.41 °C 0.35 °C 0.31 °C 1.9 °C 0.6 °C 0.36 °C 0.22 °C 0.15 °C 0.095 °C 0.08 °C	Comparison to Ectron 1140A Thermocouple Calibrator/Simulator
Electrical Simulation of RTD Indicating Devices – Source ¹	Pt 385, 100 Ω (-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C Pt 385, 200 Ω -200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C Pt 385, 500 Ω (-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.039 °C 0.039 °C 0.054 °C 0.07 °C 0.078 °C 0.093 °C 0.18 °C 0.031 °C 0.031 °C 0.031 °C 0.039 °C 0.093 °C 0.1 °C 0.11 °C 0.12 °C 0.031 °C 0.039 °C 0.039 °C 0.047 °C 0.062 °C 0.062 °C 0.07 °C 0.085 °C	Comparison to Fluke 5522A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicating Devices – Source ¹	Pt 385, 1 000 Ω		Comparison to Fluke 5522A Multiproduct Calibrator
	(-200 to -80) °C	0.023 °C	
	(-80 to 0) °C	0.023 °C	
	(0 to 100) °C	0.031 °C	
	(100 to 260) °C	0.039 °C	
	(260 to 300) °C	0.047 °C	
	(300 to 400) °C	0.054 °C	
	(400 to 600) °C	0.054 °C	
	(600 to 630) °C	0.18 °C	
	Pt 3916, 100 Ω		
	(-200 to -190) °C	0.19 °C	
	(-190 to -80) °C	0.031 °C	
	(-80 to 0) °C	0.039 °C	
	(0 to 100) °C	0.047 °C	
	(100 to 260) °C	0.054 °C	
	(260 to 300) °C	0.062 °C	
	(300 to 400) °C	0.07 °C	
	(400 to 600) °C	0.078 °C	
	(600 to 630) °C	0.018 °C	
	Pt 3926, 100 Ω		
	(-200 to -80) °C	0.039 °C	
	(-80 to 0) °C	0.039 °C	
	(0 to 100) °C	0.054 °C	
	(100 to 300) °C	0.07 °C	
(300 to 400) °C	0.078 °C		
(400 to 630) °C	0.093 °C		
PtNi 385, 120 Ω			
(-80 to 0) °C	0.062 °C		
(0 to 100) °C	0.062 °C		
(100 to 260) °C	0.1 °C		
Cu 427, 10 Ω			
(-100 to 260) °C	0.23 °C		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Power – Source ¹ 330 μW to 330 mA	11 μW to 1.1 mW (1.1 to 110) mW 110 mW to 110 W (110 to 330) W	0.024 % of reading 0.027 % of reading 0.024 % of reading 0.018 % of reading	Comparison to Fluke 5522A Multiproduct Calibrator
330 mA to 3 A	11 μW to 110 mW 110 mW to 990 W 1 W to 3 kW	0.044 % of reading 0.053 % of reading 0.009 6 % of reading	
(3 to 20.5) A	99 mW to 0.99 W 0.99 W to 6.8 kW 6.8 W to 20.5 kW	0.088 % of reading 0.07 % of reading 0.04 % of reading	
AC Power – Source ^{1,2} PF = 1 (3.3 to 9) mA	(10 to 65) Hz (0.11 mW to 3) mW 3 mW to 9 W	0.13 % of reading 0.077 % of reading	Comparison to Fluke 5522A Multiproduct Calibrator
(9 to 33) mA	(10 to 65) W (0.3 to 10) mW 10 mW to 33 W	0.089 % of reading 0.077 % of reading	
AC Power – Source ^{1,2} PF = 1 (33 to 90) mA	(10 to 65) Hz (1 to 30) mW 30 mW to 90 W	0.071 % of reading 0.057 % of reading	Comparison to Fluke 5522A Multiproduct Calibrator
(90 to 330) mA	(10 to 65) Hz (3 to 100) mW 100 mW to 300 W	0.089 % of reading 0.078 % of reading	
330 mA to 0.9 A	(10 to 65) Hz (11 to 300) mW 300 mW to 900 W	0.071 % of reading 0.081 % of reading	
(0.9 to 2.2) A	(10 to 65) Hz 30 mW to 0.72 W 0.72 W to 2 kW	0.089 % of reading 0.079 % of reading	
(2.2 to 4.5) A	(10 to 65) Hz 80 mW to 1.4 W 1.4 W to 4.5 kW	0.088 % of reading 0.18 % of reading	
(4.5 to 20.5) A	(10 to 65) Hz 150 mW to 6.7 W 6.7 W to 20 kW	0.17 % of reading 0.17 % of reading	



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment	
Oscilloscopes ^{1,3} Leveled Sine Wave into 50 Ω load	5 mVp-p to 5.5 Vp-p 50 kHz 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz 5.0 mVp-p to 3.5 Vp-p 600 MHz to 1.1 GHz	1.8 % of reading + 0.23 mV 2.8 % of reading + 0.23 mV 3.2 % of reading + 0.23 mV 4 % of reading + 0.23 mV 5.5 % of reading + 0.23 mV	Comparison to Fluke 5522A/SC1100 Multiproduct Calibrator	
Bandwidth/Flatness (50 kHz Reference) into 50 Ω load	5 mVp-p to 5.5 Vp-p 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz 5.0 mVp-p to 3.5 Vp-p 600 MHz to 1.1 GHz	1.4 % of reading + 78 μV 1.8 % of reading + 78 μV 3.2 % of reading + 78 μV 4.0 % of reading + 78 μV		
Input Impedance – Measure	(40 to 60) Ω 500 kΩ to 1.5 MΩ	0.082 % of reading 0.081 % of reading		
Input Capacitance – Measure	(5 to 50) pF	3.9 % of reading + 0.39 pF		
Oscilloscopes ^{1,3} Waveform Generator (Sine, Square, Triangle) Amplitude	10 Hz to 10 kHz into 50 Ω load into 1 MΩ load	1.8 mVp-p to 2.5 Vp-p 1.8 mVp-p to 55 Vp-p		2.3 % of reading + 78 μV 2.3 % of reading + 78 μV
Frequency	10 Hz to 10 kHz	0.0019 % of reading + 12 mHz		

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Calipers ¹ Travel (Outside, Inside, Depth, Step) Jaw Flatness Jaw Parallelism	(0.05 to 1) in (1 to 9) in	(13 + 1L) μin (8 + 5L) μin	Comparisons to Gage Blocks, Long Gage Blocks
	(4 to 15) in (15 to 40) in	(10 + 5L) μin (11 + 5L) μin	
	Up to 1 inD	4.4 μin	Optical Flats
	Up to 1 inD	34 μin	Gage Pins
Micrometers ¹ Travel (Outside, Inside, Depth) Anvil Flatness Anvil Parallelism	(0.05 to 1) in (1 to 9) in	(13 + 1L) μin (8 + 5L) μin	Comparisons to Gage Blocks, Long Gage Blocks
	(4 to 15) in (15 to 40) in	(10 + 5L) μin (11 + 5L) μin	
	Up to 1 inD	4.4 μin	Optical Flats
	Up to 1 inD	6.5 μin	Optical Parallels
Indicators ^{1,3} Digital, Dial, Drop, Test	(0 to 0.05) in	5.6 μin	Comparison to Universal Length Measuring Machine
Indicators ^{1,3} Digital, Dial, Drop, Test	up to 1 in (1 to 5) in	34 μin (60 + 2L) μin	Comparison to Gage Blocks, Stand
Length Single Axis ³ Outside Dimension Inside Dimension	(0 to 1) in (1 to 7) in (7 to 12) in	(7.3 + 1L) μin (5.3 + 3.3L) μin (2 + 4L) μin	Comparison to Universal Length Measuring Machine
	(0.04 to 1) in (1 to 2.5) in (2.5 to 10) in (10 to 14) in	(10 + 1L) μin (10 + 4L) μin (15 + 3L) μin (27 + 3L) μin	
Thread Wires	2 TPI to 120 TPI (0.008 33 to 0.5) in	12 μin	Comparison to Universal Length Measuring Machine

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Cylindrical Plug Gages ⁴ (Outside Diameter)	Up to 1 in (1 to 7) in	13 μin (11 + 3L) μin	Comparison to Universal Length Measuring Machine
Pin Gages (Outside Diameter)	(0.01 to 0.04) in (0.04 to 0.5) in (0.5 to 1) in (1 to 2) in	40 μin 39 μin 39 μin 41 μin	Non-contact Method using Laser Micrometer.
Optical Comparators ³ Length	Up to 8 in	(100 + 14L) μin	Comparisons to Calibration Grids
Squareness	(0.04 to 1) in	(120 + 1.5L) μin	Calibration Grids
Thread Plug Gages ³ Pitch Diameter, 60° Thread	Up to 1 in (1 to 4) in (4 to 7) in	82 μin 84 μin 88 μin	Comparisons to Master Thread Wires, Super-micrometer [®] Model C
Major Diameter	Up to 1 in (1 to 7) in	36 μin (33 + 3L) μin	
Step Height	Up to 1 in	62 μin	Gage Blocks, Test Stand
Thread Ring Gages Inner Pitch Diameter	Up to 1 in (1 to 4) in (4 to 7) in	88 μin 85 μin 93 μin	Tactile fit using Master Plug Gage
Ring Gages ³ Inside Diameter	(0.04 to 1) in (1 to 2.5) in (2.5 to 5) in	(9 + 1L) μin (10 + 3L) μin (15 + 3L) μin	Comparison to Universal Length Measuring Machine, Working Reference Rings
Tapered Thread Plug Pitch Diameter Taper	Up to 3 in	90 μin	Comparison to Universal Length Measuring Machine, Thread Wires

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Torque Drivers, Indicators ¹	(5 to 50) ozf·in (50 to 200) ozf·in (4 to 400) lbf·in	1.6 % of reading 0.98% of reading 0.56% of reading	Comparison to CDI Torque Measuring System
Torque Wrenches ¹	4 lbf·in to 600 lbf·ft	0.44% of reading	Comparison to CDI Torque Measuring System
Mass Determination (SI Units)	1 mg 2 mg 3 mg 5 mg 10 mg 20 mg 30 mg 50 mg 100 mg 200 mg 300 mg 500 mg 1 g 2 g 3 g 5 g 10 g 20 g 30 g 50 g 100 g 200 g 300 g 500 g 1 kg 2 kg 3 kg 5 kg 10 kg	1.7 µg 1.7 µg 1.7 µg 1.7 µg 1.7 µg 1.7 µg 1.7 µg 1.7 µg 1.7 µg 1.7 µg 1.7 µg 1.7 µg 4.3 µg 4.3 µg 4.4 µg 5.2 µg 8.6 µg 12 µg 13 µg 17 µg 35 µg 0.1 mg 0.13 mg 0.17 mg 0.33 mg 0.98 mg 1.2 mg 1.7 mg 3.4 mg	Double Substitution Method; Reference Weights, Electronic Balances

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Mass Determination (SI Units)	1 mg	3.6 µg	Single Substitution Method; Reference Weights, Electronic Balances
	2 mg	3.6 µg	
	3 mg	3.6 µg	
	5 mg	3.6 µg	
	10 mg	3.6 µg	
	20 mg	3.6 µg	
	30 mg	3.6 µg	
	50 mg	3.6 µg	
	100 mg	3.6 µg	
	200 mg	3.6 µg	
	300 mg	3.6 µg	
	500 mg	3.6 µg	
	1 g	11 µg	
	2 g	11 µg	
	3 g	11 µg	
	5 g	11 µg	
	10 g	18 µg	
	20 g	26 µg	
	30 g	26 µg	
	50 g	41 µg	
	100 g	84 µg	
	200 g	0.2 mg	
	300 g	0.27 mg	
	500 g	0.41 mg	
	1 kg	0.83 mg	
2 kg	1.9 mg		
3 kg	2.7 mg		
5 kg	4.1 mg		
10 kg	8.3 mg		
20 kg	0.23 g		
25 kg	0.23 g		
Mass Determination ⁵ (Avoirdupois)	1 lb	34 mg	Comparison to ASTM E617 Class 0 Weights, Electronic Balances
	2 lb	34 mg	
	3 lb	34 mg	
	5 lb	34 mg	
	10 lb	34 mg	
	20 lb	34 mg	
	30 lb	35 mg	
	50 lb	41 mg	

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Scales and Balances ^{1,7} (SI)	Up to 500 mg 500 mg to 5 g (5 to 10) g (10 to 30) g (30 to 50) g (50 to 100) g 100 g to 1 kg (1 to 2) kg (2 to 3) kg (3 to 5) kg (5 to 10) kg (10 to 11) kg	1.7 µg 5.2 µg 8.4 µg 22 µg 24 µg 39 µg 2 mg 2.2 mg 2.3 mg 2.6 mg 3.9 mg 0.000 31 % of reading	ASTM E617 Class 1 weights and internal calibration procedure utilized for calibration of the weighing system.
Scales and Balances ^{1,6} (Avoirdupois)	Up to 0.5 oz (0.5 to 1) oz (1 to 2) oz (2 to 4) oz (4 to 8) oz 8 oz to 1 lb (1 to 2) lb (2 to 3) lb (3 to 5) lb (5 to 10) lb (10 to 20) lb (20 to 22) lb	0.000 049 oz 0.000 102 oz 0.000 201 oz 0.000 42 oz 0.000 81 oz 0.001 62 oz 0.000 201 lb 0.000 309 lb 0.000 507 lb 0.001 014 lb 0.002 006 lb 0.003 086 lb	ASTM E617 Class 1 weights and internal calibration procedure utilized for the calibration of the weighing system.
Scales and Balances ^{1,7} (Avoirdupois)	(5 to 1 200) lb	0.012 % of reading	NIST Class F weights and internal calibration procedure utilized for the calibration of the weighing system.
Pneumatic Pressure Devices (Gauge) at 20 °C	(-1 to 1) inH ₂ O	0.001 2 inH ₂ O	Comparison to Additel ADT761-LLP, Pressure Module
Pneumatic Pressure Devices (Gauge) at 20 °C	(-60 to -36) inH ₂ O (-36 to 36) inH ₂ O (36 to 60) inH ₂ O	0.01% of reading + 0.003 3 inH ₂ O 0.0048 inH ₂ O 0.01% of reading + 0.003 3 inH ₂ O	Comparison to Fluke 6720A Pressure Controller
Pneumatic Pressure Devices (Gauge)	(-14.5 to -4) psig (-4 to 8.5) psig (8.5 to 100) psig (100 to 300) psig (300 to 1 000) psig	0.01 % of reading + 0.002 2 psi 0.002 7 psi 0.01% of reading + 0.003 2 psi 0.038 psi 0.01 % of reading + 0.014 psi	Comparison to Fluke 6270A Pressure Controller

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Hydraulic Pressure Devices (Gauge)	(200 to 1 600) psig (1 600 to 16 200) psig	0.091 psi 0.005 9 % of reading	Comparison to Deadweight Tester
Pneumatic Pressure Devices (Absolute)	Up to 4.5 psia (4.5 to 15) psia (15 to 30) psia (30 to 100) psia (100 to 300) psia (300 to 1 000) psia	0.001 6 psi 0.006 6 % of reading + 0.001 8 psi 0.006 6 % of reading + 0.003 2 psi 0.006 6 % of reading + 0.006 8 psi 0.086 psi 0.006 6 % of reading + 0.068 psi	Comparison to Fluke 6270A Pressure Controller

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Humidity – Measure ¹	(15 to 25) °C (10 to 90) %RH (90 to 98) %RH	1.3 %RH 2 %RH	Direct measure using Master Thermohygrometer
Humidity – Generate	(-10 to 15) °C (10 to 75) %RH (75 to 95) %RH (15 to 35) °C (10 to 95) %RH (35 to 70) °C (10 to 50) %RH (50 to 75) %RH (75 to 95) %RH	0.5 %RH 0.65 %RH 0.5 %RH 0.5 %RH 0.7 %RH 0.85 %RH	Comparison to Humidity Generator
Temperature – Measure ¹	(-195 to 155) °C (155 to 420) °C (420 to 660) °C	0.023 °C 0.033 °C 0.045 °C	Comparison to Fluke 1502A Temperature Readout, AccuMac AM1760 Secondary SPRT
Temperature – Source ¹	(-40 to 0) °C (0 to 100) °C (155 to 420) °C (420 to 660) °C	0.041 °C 0.02% of reading + 0.037°C 0.056% of reading + 0.064°C 0.071% of reading	Comparison to Fluke 1502A Temperature Readout, AccuMac AM1760 Secondary SPRT, Additel ADT878 Reference Dry Well Calibrator

Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Frequency – Reference	10 MHz	0.59 nHz/Hz	Comparison to Stanford Research FS725 Rubidium Frequency Oscillator
Period – Source	(1 to 100) s	58 ns/s	Comparison to Keysight 33250A Function/Arbitrary Waveform Generator, Stanford Research FS725 Rubidium Frequency Oscillator
Period – Measure	(1 to 100) s	45 μs	Comparison to HP 53132A Universal Counter, Stanford Research FS725 Rubidium Frequency Oscillator
Frequency – Source	1 Hz to 80 MHz	58 nHz/Hz	Comparison to Keysight 33250A Function/Arbitrary Waveform Generator, Stanford Research FS725 Rubidium Frequency Oscillator
Frequency – Measure	1 Hz to 10 kHz 10 kHz to 10 MHz (10 to 350) MHz	0.64 nHz/Hz + 4.5 μHz 0.64 nHz/Hz + 5 μHz 0.64 nHz/Hz	Comparison to HP 53230A Universal Counter, Stanford Research FS725 Rubidium Frequency
AC Duty Cycle – Source ¹ Square Wave: < 3.3 Vp-p Freq: 0.1 Hz to 100 kHz	(1 to 10) % Duty Cycle 10 μs to 100 s (10 to 49) % Duty Cycle 10 μs to 100 s 50 % Duty Cycle 10 μs to 100 s (51 to 90) % Duty Cycle 10 μs to 100 s (90 to 99) % Duty Cycle 10 μs to 100 s	0.62 % of reading + 78 ns 0.039 % of reading + 78 ns 0.001 6 % of reading + 78 ns 0.039 % of reading + 78 ns 0.62 % of reading + 78 ns	Comparison to Fluke 5522A Multiproduct Calibrator

Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Non-Contact Rate of Rotation ⁵	(5 to 99.999) rpm (100.00 to 999.99) rpm (1 000.0 to 9 999.9) rpm (10 000 to 99 999) rpm (100 000 to 200 000) rpm	0.012 % of reading + 0.0012 rpm 0.012 % of reading + 0.012 rpm 0.012 % of reading + 0.12 rpm 0.014 % of reading + 1.2 rpm 0.014 % of reading + 12 rpm	Comparison to Optical Tachometer
Stopwatches/Timers	Up to 599 s/mon	58 ms/d	Comparison to Vibrograf TM-4500 Timometer

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

- On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
- The uncertainties shown are for the most favorable conditions. There is an increase in uncertainty that corresponds to the laboratory's AC voltage and current uncertainties at different frequencies other than the ones shown. Power factors (PF) other than the one shown contribute to the power uncertainty. PF is related to the cosine of phase. Therefore, uncertainties track the laboratory's phase uncertainty closely at PF near one but are magnified heavily as PF approaches zero. The lab may also report reactive power, apparent power, and power factor under this accreditation. If needed, contact the laboratory for more information regarding uncertainties at frequency and power factor combinations other than the ones shown.
- Dimensional Lab Environment ± 2 °F.
- The stated uncertainty is the laboratory's ability to source a fast rise pulse that is approximately 250 ps. In the typical application of measuring rise time of an oscilloscope, this value is one of the contributing factors, but other factors are derived from the DUT.
- D = diameter; L = length in inches; rpm = revolutions per minute.
- The CMC for scales and balances is highly dependent upon the resolution of the unit under test. The CMC presented here does not include the resolution of the unit under test. The resolution will be included in the reported measurement uncertainty at the time of calibration.
- The CMC presented here does not include the Resolution of the Device Under Test (DUT). The Resolution will be added at the time of calibration in the Measurement Uncertainty (MU).
- Unless otherwise specified in the far-right column, the calibration method/procedure utilized by the laboratory was developed internally.
- The legal entity of this location is Transcat, Inc.



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